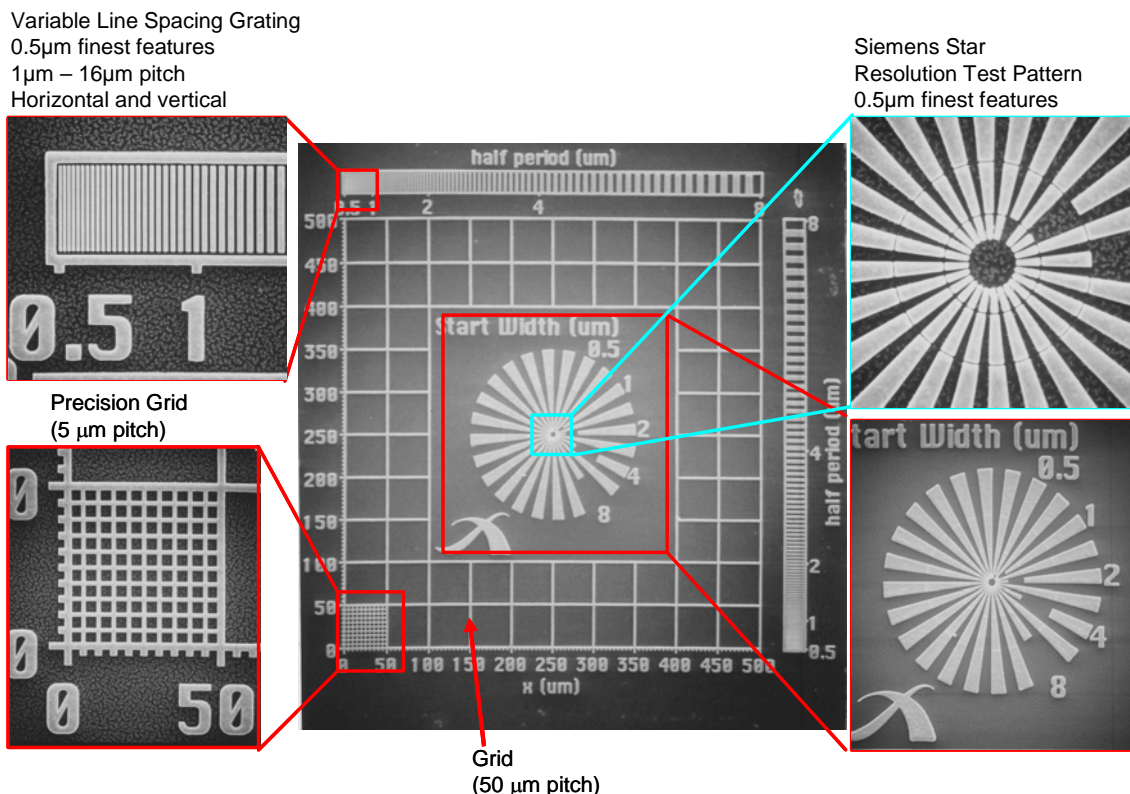


Resolution / Calibration Standard X500-200-30



Xradia, Inc. offers a high-resolution and calibration standard test pattern for calibrating and evaluating the spatial resolution and performance of x-ray imaging systems. The test pattern is fabricated using the same process that enables the manufacture of Xradia's zone plate lenses that have the highest performance in terms of spatial resolution and focusing efficiency for multi-keV and high-energy x-ray imaging/focusing applications. The test pattern has a variety of structures that enable resolution tests, modulation transfer measurements, length scale calibration and field distortion measurements.

The finest feature size on the pattern is $0.5\mu\text{m}$. All test structures are labeled for easy identification. The large thickness of this pattern is ideal for high energy x-ray applications above 10keV.



Ordering And Price Information

(revised 1-Sep-2004)

Model Number	Parameters				Price (\$k)
	Structure Material	Smallest Feature (μm)	Star Diameter (μm)	Structure Height (nominal nm)	
X500-200-30	Gold	0.5	200	3000nm	7

Notes: The test pattern is fabricated on a free standing, low stress Si_3N_4 membrane with a thickness of 330 nm. Delivery is 3-4 weeks ARO.